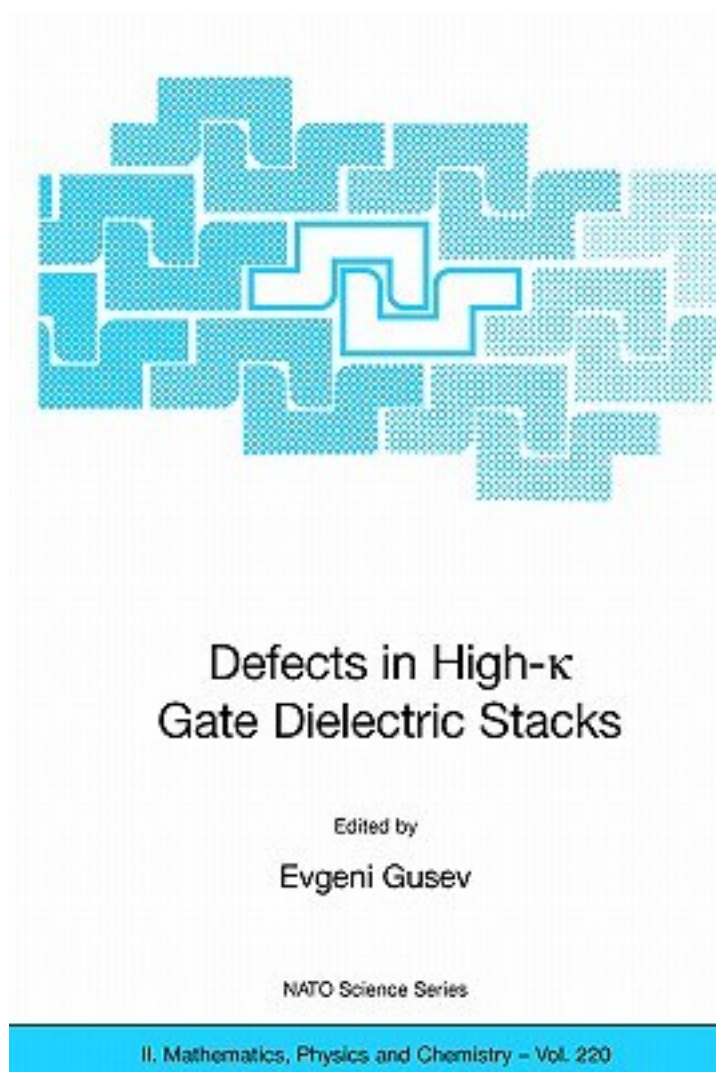


# Defects in High- $\kappa$ Gate Dielectric Stacks



[Defects in High-k Gate Dielectric Stacks 下载链接1](#)

著者:Gusev, Evgeni (EDT)

出版者:Springer Verlag

出版时间:

装帧:Pap

isbn:9781402043666

作者介绍:

目录:

[Defects in High-k Gate Dielectric Stacks\\_下载链接1](#)

标签

评论

-----  
[Defects in High-k Gate Dielectric Stacks\\_下载链接1](#)

书评

-----  
[Defects in High-k Gate Dielectric Stacks\\_下载链接1](#)